

Professional Service:

- 2015- Member, Participating User Team at NSLS-II ISR Beamline
- 2015- Argonne National Lab. CNM Proposal Evaluation Board
- 2010- Spokesperson, NSLS-II *In-Situ* Resonant (ISR) Beamline Advisory Team
- 2008-2015 Member, NSLS-II Coherent Hard X-ray (CHX) Beamline Advisory Team
- 2006-2014 Spokesperson, NSLS Surface Growth Processes Contributing User Group
- 2002-2014 Member, NSLS Scattering Proposal Review Panel
- 2013-2014 Member, Brookhaven Photon Sciences Users Executive Committee
- 2011-2013 Member, APS Directorate Review Panel (University of Chicago – ANL)
- 2006-2008 Chair, Advanced Photon Source Condensed Matter Review Panel
- 2005-2006 Member, Advanced Photon Source Condensed Matter Review Panel
- 2008 Organizer, *Workshop on Real-Time X-ray Studies of Materials* at NSLS Users Meeting
- 2008 Organizer, *Symposium on Grazing Incidence Small-Angle X-ray Scattering* at Fall MRS Meeting
- 2006 Co-Organizer, Spring 2006 Joint Meeting of the New England Section of APS
- 2006 Chair, Nominating Committee of the New England Section of APS
- 2005 Chair, New England Section of the American Physical Society
- 2004 Vice-Chair, New England Section of the American Physical Society
- 2004-2009 Member, Linear Coherent Light Source Nanoscale Dynamics Team
- 2002 Co-Organizer, *Workshop on Real-Time X-ray Studies of Materials* at NSLS Users Meeting
- 2002 Co-Organizer, *Synchrotron Applications* Session at Denver X-ray Conference

Current Ph.D. Students: C. Wagenbach, M. Mokhtarzadeh

Former Ph.D. Students: Y. Xie (Suzhou Inst., China), G. Morales, O. Malis (Purdue), X. Wang (Scotiabank), A. Özcan (IBM Research), Y. Wang (TSMC North America), G. Ozaydin-Ince (Sabanci Univ., Turkey), C. Sanborn (Athena), E. Anzenberg (SKOUT), J. Davis, G. Erdem Rainville (Lam Research)

Former Postdoctoral Researchers: N. Bouet (Brookhaven Natl. Lab.), L. Colakerol Arslan (Gebze Inst. Tech., Turkey), A. DeMasi (Signature Science)

PUBLICATIONS

115. “Real-time Growth Study of Plasma Assisted Atomic Layer Epitaxy of InN Films by Synchrotron X-ray Methods”, N. Nepal, V.R. Anderson, S.D. Johnson, B.P. Downey, D.J. Meyer, A. DeMasi, Z.R. Robinson, K.F. Ludwig and C.R. Eddy, Jr., accepted at *J. Vac. Sci. Technol. A*.
114. “A Case Study of ALD Encapsulation of Quantum Dots: Embedding Supported CdSe/CdS/ZnS Quantum Dots in a ZnO Matrix”, K. Devloo-Casier, P. Geiregat, K. Ludwig, K. Van Stiphout, A. Vantomme, Z. Hens, C. Detavernier, J. Dendooven, *J. Phys. Chem. C* **120**, 18039 (2016).
113. “Chemical Characterization of Surface Precipitates in $\text{La}_{0.7}\text{Sr}_{0.3-x}\text{Co}_{0.2}\text{Fe}_{0.8}\text{O}_{3-\delta}$ as Cathode Material for Solid Oxide Fuel Cells”, Y. Yu, A. Nikiforov, T. Kasper, J. Woicik, K.F. Ludwig, S. Gopalan, U. Pal and S. Basu, *Journal of Power Sources* **333**, 247 (2016).
112. “Effect of Sr Content and Strain on Sr Surface Segregation of $\text{La}_{1-x}\text{Sr}_x\text{Co}_{0.2}\text{Fe}_{0.8}\text{O}_{3-\delta}$ as Cathode Material for Solid Oxide Fuel Cells, Y. Yu, K.F. Ludwig, J.C. Woicik, S. Gopalan, U. Pal, T.C. Kaspar and S.N. Basu, *ACS Applied Materials and Interfaces* **8**, 26704 (2016).
111. “Using Coherent X-rays to Directly Measure the Propagation Velocity of Defects During Thin Film Deposition”, Jeffrey G. Ulbrandt, Meliha G. Rainville, Christa Hoskin, Suresh Narayanan, Alec R. Sandy, Hua Zhou, Karl F. Ludwig, Jr. and Randall L. Headrick, *Nature Physics* **12**, 794 (2016).
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109. “Vacancy Assisted SrO Formation on $\text{La}_{0.8}\text{Sr}_{0.2}\text{Co}_{0.2}\text{Fe}_{0.8}\text{O}_3$ - Surfaces – A Synchrotron Photoemission Study”, J. Kuyyalil, D. Newby, Jr., J. Laverock, Y. Yu, D. Cetin, S. Basu, K. Ludwig and K.E. Smith, *Surf. Sci.* **642**, 33 (2015).
108. “Surface Evolution of Lanthanum Strontium Cobalt Ferrite Thin Films at Low Temperatures”, D. Newby Jr., J. Kuyyalil, J. Laverock, K.F. Ludwig, Y. Yu, J. Davis, S. Gopalan, U. Pal, S. Basu and K.E. Smith, *Thin Solid Films* **589**, 655 (2015).
107. “Ion beam nanopatterning of III-V semiconductors: consistency of experimental and simulation trends within a chemistry-driven theory”, O. El-Atwani, S. Norris, K. Ludwig, S. Gonderman and J.P. Allain, *Scientific Reports* **5**, 18207 (2015).
106. “Real-Time X-ray Studies of Indium Island Growth Kinetics”, A. DeMasi, M. Rainville and K.F. Ludwig, *J. Vac. Sci. and Technol. A* **33**, 021406 (2015).
105. “Atomic Layer Deposition-Based Tuning of the Pore Size in MesoPorous Thin Films Studied by In Situ Grazing Incidence Small Angle X-ray Scattering”, J. Dendooven, K. Devloo-Casier, M. Ide, K. Grandfield, M. Kurttepel, K.F. Ludwig, S. Bals, P. Van Der Voort and C. Detavernier, *Nanoscale* **6**, 14991 (2014).
104. “Predicting Oxygen Vacancy Non-Stoichiometric Concentration in Perovskites from First Principles”, Heng Luo, Yongwoo Shin, Yang Yu, Deniz Cetin, Karl Ludwig, Uday Pal, Soumendhra N. Basu, Srikanth Gopalan, Xi Lin, *Appl. Surf. Sci.* **323**, 65 (2014).
103. “Model-Independent Test of the Crater Function Theory of Surface Morphology Evolution during Ion Bombardment”, E. Anzenberg, J. Perkinson, M. Aziz and K. Ludwig, *Phys. Rev. B* **89**, 115433 (2014).
102. “Effect of Atmospheric CO_2 on Surface Segregation and Phase Formation in $\text{La}_{0.6}\text{Sr}_{0.4}\text{Co}_{0.2}\text{Fe}_{0.8}\text{O}_{3-\delta}$ Thin Films”, Yang Yu, Heng Luo, Deniz Cetin, Xi Lin, Karl Ludwig, Uday Pal, Srikanth Gopalan, Soumendhra Basu, *Appl. Surf. Sci.* **323**, 71 (2014).

101. "Effect of Carbon Dioxide on the Cathodic Performance of Solid Oxide Fuel Cells", Y. Yu, H. Luo, D. Cetin, X. Lin, K. Ludwig, S. Basu, U. Pal, S. Gopalan, *ECS Trans.* **61**, 131 (2014).
100. "In-Situ Synchrotron Based X-ray Techniques as Monitoring Tools for Atomic Layer Deposition – A Review", K. Devloo-Casier, K.F. Ludwig, C. Detavernier and J. Dendooven, *J. Vac. Sci. Technol. A* **32**, 010801 (2014).
99. "Atomic Layer Deposition of TiO₂ on Surface Modified Nanoporous Low-k Films", E. Levrau, K. Devloo-Casier, J. Dendooven, K. Ludwig, P. Verdonck, J. Meersschaut, M. Baklanov and C. Detavernier, *Langmuir* **29**, 12284 (2013).
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97. "Development of AlGa_N-Based Graded-Index-Separate-Confinement Heterostructure Deep UV Emitters by Molecular Beam Epitaxy", H. Sun, J. Woodward, J. Yin, A. Moldawer, E. Pecora, A. Nikiforov, L. Dal Negro, R. Paiella, K. Ludwig, D. Smith and T.D. Moustakas, *J. Vac. Sci. Technol. B* **31**, 03C117-1 (2013).
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95. "Nanoscale Surface Pattern Formation Kinetics on Germanium Irradiated by Kr⁺ Ions", E. Anzenberg, J.C. Perkinson, C.S. Madi, M.J. Aziz and K.F. Ludwig, Jr., *Phys. Rev. B* **86**, 245412 (2012).
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82. "Growth Kinetics of AlN and GaN Films Grown by Molecular Beam Epitaxy on R-Plane Sapphire Substrates", R. Chandrasekaran, T.D. Moustakas, A. Ozcan, K. Ludwig, L. Zhou and D. Smith, *J. Appl. Phys.* **108**, 043501 (2010).
81. "In Situ X-ray Studies of Native and Mo-Seeded Surface Nanostructuring during Ion Bombardment of Si(100)", G. Ozaydin-Ince and K.F. Ludwig, Jr., *J. Phys.: Condens. Matter.* **21**, 224008 (2009).
80. "Mechanisms of Pattern Formation and Smoothing Induced by Ion-Beam Erosion", Hua Zhou, Lan Zhou, Gozde Ozaydin, Karl F. Ludwig, Jr., and Randall Headrick, *Phys. Rev. B* **78**, 165404 (2008).
79. "Effects of Mo Seeding on the Formation of Si Nanodots During Low-Energy Ion Bombardment", Gozde Ozaydin, Karl F. Ludwig, Jr., Hua Zhou and Randall L. Headrick, *Journal of Vacuum Science and Technology B* **26**, 551 (2008).
78. "Real-Time Studies of Gallium Adsorption and Desorption Kinetics by Grazing Incidence Small-Angle X-ray Scattering and X-ray Fluorescence", Yiyi Wang, Ahmet Ozcan, Karl Ludwig and Anirban Bhattacharyya, *J. Appl. Phys.* **103**, 103538 (2008).
77. "Transition Behavior of Surface Morphology Evolution of Si(100) During Low-Energy Normal-Incidence Ar⁺ Ion Bombardment", Gozde Ozaydin, Karl F. Ludwig, Jr., Hua Zhou, Lan Zhou and Randall L. Headrick, *J. Appl. Phys.* **103**, 033512 (2008).
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75. "Real-Time X-Ray Studies of Gallium Nitride Nanodot Formation by Droplet Heteroepitaxy", Yiyi Wang, Ahmet S. Özcan, Christopher Sanborn, Karl F. Ludwig, Anirban Bhattacharyya, Ramya Chandrasekaran, Theodore D. Moustakas, Lin Zhou and David J. Smith, *J. Appl. Phys.* **102**, 073522 (2007).
74. "Real-Time X-ray Studies of the Growth of Mo-Seeded Si nanodots by Low-Energy Ion Bombardment", Gozde Ozaydin, Ahmet S. Özcan and Yiyi Wang, Karl F. Ludwig, Hua Zhou and Randall L. Headrick, *Nucl. Inst. Meth. Phys. Res. B* **264**, 47 (2007).
73. "Experimental Methods: High-Resolution Scattering Methods and Time-Resolved Diffraction", B. Sepiol and K. Ludwig in *Alloy Physics A Comprehensive Reference*, W. Pfeiler, Ed. (Wiley, 2007).
72. "Growth of on-polar (11-20) and semi-polar (11-26) AlN and GaN films on R-Plane sapphire", R. Chandrasekaran, A.S. Ozcan, D. Deniz, K.F. Ludwig and T.D. Moustakas, *Phys. Stat. Sol. (c)* **4**, 1689 (2007).
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 69. "Real-Time X-Ray Studies of Gallium Adsorption and Desorption", Ahmet S. Özcan, Yiyi Wang, Gozde Ozaydin, Karl F. Ludwig, Anirban Bhattacharyya, Theodore D. Moustakas and D. Peter Siddons, *J. Appl. Phys.* **100**, 084307 (2006).
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